


<p style="text-align: center;"><b>Search Notes</b></p> 	<p><b>Application/Control No.</b></p> <p>10618302</p>	<p><b>Applicant(s)/Patent Under Reexamination</b></p> <p>HONKEN ET AL.</p>
	<p><b>Examiner</b></p> <p>Duong, Frank</p>	<p><b>Art Unit</b></p> <p>2616</p>

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST Search (see printout)	07/04/08	FD
Inventorship Search (see printout)	07/04/08	FD
IEEE/Internet Search	07/04/08	FD

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
	Interference Search (see printout)	07/04/08	FD